## Notice of References Cited Application/Control No. 10/557,350 Examiner MATTHEW G. KAYRISH Applicant(s)/Patent Under Reexamination STEK ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,374,860	12-1994	Llewellyn, William D.	327/276
*	В	US-7,151,727	12-2006	limura et al.	369/47.22
*	C	US-6,868,053	03-2005	Gushima et al.	369/59.11
*	D	US-6,724,708	04-2004	Ishibashi et al.	369/59.25
*	Е	US-2002/0180547	12-2002	Staszewski et al.	332/115
*	F	US-2002/0067678	06-2002	Jeon et al.	369/59.25
*	G	US-5,761,254	06-1998	Behrin, Michael N.	375/355
*	Η	US-6,246,714	06-2001	Okamoto, Naoki	375/142
*	I	US-6,650,689	11-2003	Oishi et al.	375/142
*	J	US-5,828,250	10-1998	Konno, Katsushi	327/116
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Ø					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.